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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	24600
Number of Logic Elements/Cells	314880
Total RAM Bits	25952256
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vsx315t-1ffg1156c

Table 2: Recommended Operating Conditions

Symbol	Description	Min	Max	Units
V_{CCINT}	Internal supply voltage relative to GND for all devices except -1L devices.	0.95	1.05	V
	For -1L commercial temperature range devices: internal supply voltage relative to GND, $T_j = 0^{\circ}\text{C}$ to $+85^{\circ}\text{C}$	0.87	0.93	V
	For -1L industrial temperature range devices: internal supply voltage relative to GND, $T_j = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}$	0.91	0.97	V
V_{CCAUX}	Auxiliary supply voltage relative to GND	2.375	2.625	V
$V_{CCO}^{(1)(2)(3)}$	Supply voltage relative to GND	1.14	2.625	V
V_{IN}	2.5V supply voltage relative to GND	GND – 0.20	2.625	V
	2.5V and below supply voltage relative to GND	GND – 0.20	$V_{CCO} + 0.2$	V
$I_{IN}^{(5)}$	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	10	mA
$V_{BATT}^{(6)}$	Battery voltage relative to GND	1.0	2.5	V
$V_{FS}^{(7)}$	External voltage supply for eFUSE programming	2.375	2.625	V
T_j	Junction temperature operating range for commercial (C) temperature devices	0	85	$^{\circ}\text{C}$
	Junction temperature operating range for extended (E) temperature devices	0	100	$^{\circ}\text{C}$
	Junction temperature operating range for industrial (I) temperature devices	–40	100	$^{\circ}\text{C}$
	Junction temperature operating range for military (M) temperature devices	–55	125	$^{\circ}\text{C}$

Notes:

1. Configuration data is retained even if V_{CCO} drops to 0V.
2. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, and 2.5V.
3. The configuration supply voltage V_{CC_CONFIG} is also known as V_{CCO_0} .
4. All voltages are relative to ground.
5. A total of 100 mA per bank should not be exceeded.
6. V_{BATT} is required only when using bitstream encryption. If battery is not used, connect V_{BATT} to either ground or V_{CCAUX} .
7. During eFUSE programming, V_{FS} must be within the recommended operating range and $T_j = +15^{\circ}\text{C}$ to $+85^{\circ}\text{C}$. Otherwise, V_{FS} can be connected to GND.

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	XC6VLX75T	45	45	45	N/A	45	45	mA
		XC6VLX130T	75	75	75	N/A	75	75	mA
		XC6VLX195T	113	113	113	N/A	113	113	mA
		XC6VLX240T	135	135	135	N/A	135	135	mA
		XC6VLX365T	191	191	191	N/A	191	191	mA
		XC6VLX550T ⁽³⁾	N/A	286	286	N/A	286	286	mA
		XC6VLX760 ⁽³⁾	N/A	387	387	N/A	387	387	mA
		XC6VSX315T	186	186	186	N/A	186	186	mA
		XC6VSX475T ⁽³⁾	N/A	279	279	N/A	279	279	mA
		XC6VHX250T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX255T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	227	227	227	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	315	315	N/A	N/A	N/A	mA
		XQ6VLX130T ⁽⁶⁾	N/A	75	N/A	75	N/A	75	mA
		XQ6VLX240T ⁽⁶⁾	N/A	135	N/A	135	N/A	135	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	286	N/A	286	mA
		XQ6VSX315T ⁽⁶⁾	N/A	186	N/A	186	N/A	186	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	279	N/A	279	mA

Notes:

- Typical values are specified at nominal voltage, 85°C junction temperatures (T_j). -1 and -2 industrial (I) grade devices have the same typical values as commercial (C) grade devices at 85°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. -1L industrial temperature range devices have the values specified in this column.
- Use the XPE tool to calculate 125°C values for -1M temperature range devices.
- The -2E extended temperature range (T_j = 0°C to +100°C) is only available in these devices. The -2I temperature range (T_j = -40°C to +100°C) is available for all other devices except the XC6VHX565T.
- The XC6VHX380T is available with both -2E and -2I temperature ranges.
- The XC6VHX565T is only available in the following temperature ranges: -1C, -1I, -2C, and -2E.
- The XQ6VLX130T, XQ6VLX240T, and XQ6VSX315T are available in -2I, -1I, -1M, and -1LI temperature ranges.
- The XQ6VLX550T and the XQ6VSX475T are only available in -1I and -1LI temperature ranges.
- Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
- If DCI or differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPE or XPower Analyzer (XPA) tools.

Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on sequence and ramp rate of the power supply.

The recommended power-on sequence for Virtex-6 devices is V_{CCINT} , V_{CCAUX} , and V_{CCO} to meet the power-up current requirements listed in Table 5. V_{CCINT} can be powered up or down at any time, but power up current specifications can vary from Table 5. The device will have no physical damage or reliability concerns if V_{CCINT} , V_{CCAUX} , and V_{CCO} sequence cannot be followed.

If the recommended power-up sequence cannot be followed and the I/Os must remain 3-stated throughout configuration, then V_{CCAUX} must be powered prior to V_{CCO} or V_{CCAUX} and V_{CCO} must be powered by the same supply. Similarly, for power-down, the reverse V_{CCAUX} and V_{CCO} sequence is recommended if the I/Os are to remain 3-stated.

The GTH transceiver supplies must be powered using a MGTHAVCC, MGTHAVCCR, MGTHAVCCPLL, and MGTHAVTT sequence. There are no sequencing requirement for these supplies with respect to the other FPGA supply voltages. For more detail see Table 27: *GTH Transceiver Power Supply Sequencing*. There are no sequencing requirements for the GTX transceivers power supplies.

Table 5 shows the minimum current, in addition to I_{CCQ} , that are required by Virtex-6 devices for proper power-on and configuration. If the current minimums shown in Table 4 and Table 5 are met, the device powers on after all three supplies have passed through their power-on reset threshold voltages. The FPGA must be configured after applying V_{CCINT} , V_{CCAUX} , and V_{CCO} for the appropriate configuration banks. Once initialized and configured, use the XPE tools to estimate current drain on these supplies.

Table 5: Power-On Current for Virtex-6 Devices

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	Units
	Typ ⁽¹⁾	Typ ⁽¹⁾	Typ ⁽¹⁾	
XC6VLX75T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VLX130T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VLX195T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VLX240T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VLX365T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VLX550T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VLX760	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VSX315T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VSX475T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VHX250T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VHX255T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VHX380T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XC6VHX565T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30$ mA per bank	mA
XQ6VLX130T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30$ mA per bank	mA
XQ6VLX240T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30$ mA per bank	mA
XQ6VLX550T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30$ mA per bank	mA
XQ6VSX315T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40$ mA per bank	mA
XQ6VSX475T	See I_{CCINTQ} in Table 4	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40$ mA per bank	mA

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

HT DC Specifications (HT_25)

Table 8: HT DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OD}	Differential Output Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	480	600	885	mV
	Differential Output Voltage for XQ devices		480	600	930	mV
ΔV_{OD}	Change in V_{OD} Magnitude		-15	—	15	mV
V_{OCM}	Output Common Mode Voltage	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	440	600	760	mV
ΔV_{OCM}	Change in V_{OCM} Magnitude		-15	—	15	mV
V_{ID}	Input Differential Voltage		200	600	1000	mV
ΔV_{ID}	Change in V_{ID} Magnitude		-15	—	15	mV
V_{ICM}	Input Common Mode Voltage		440	600	780	mV
ΔV_{ICM}	Change in V_{ICM} Magnitude		-15	—	15	mV

LVDS DC Specifications (LVDS_25)

Table 9: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	—	—	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.825	—	—	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.3	1.2	2.2	V

Extended LVDS DC Specifications (LVDSEXT_25)

Table 10: Extended LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	—	—	1.785	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.715	—	—	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	350	—	840	mV
	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High for XQ devices		350	—	850	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	—	1000	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.3	1.2	2.2	V

LVPECL DC Specifications (LVPECL_25)

These values are valid when driving a 100Ω differential load only, i.e., a 100Ω resistor between the two receiver pins. The V_{OH} levels are 200 mV below standard LVPECL levels and are compatible with devices tolerant of lower common-mode ranges. [Table 11](#) summarizes the DC output specifications of LVPECL. For more information on using LVPECL, see [UG361: Virtex-6 FPGA SelectIO Resources User Guide](#).

Table 11: LVPECL DC Specifications

Symbol	DC Parameter	Min	Typ	Max	Units
V_{OH}	Output High Voltage	$V_{CC} - 1.025$	1.545	$V_{CC} - 0.88$	V
V_{OL}	Output Low Voltage	$V_{CC} - 1.81$	0.795	$V_{CC} - 1.62$	V
V_{ICM}	Input Common-Mode Voltage	0.6	—	2.2	V
V_{IDIFF}	Differential Input Voltage ⁽¹⁾⁽²⁾	0.100	—	1.5	V

Notes:

1. Recommended input maximum voltage not to exceed $V_{CCAUX} + 0.2V$.
2. Recommended input minimum voltage not to go below $-0.5V$.

eFUSE Read Endurance

[Table 12](#) lists the maximum number of read cycle operations expected. For more information, see [UG360: Virtex-6 FPGA Configuration User Guide](#).

Table 12: eFUSE Read Endurance

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
DNA_CYCLES	Number of DNA_PORT READ operations or JTAG ISC_DNA read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles
AES_CYCLES	Number of JTAG FUSE_KEY or FUSE_CNTL read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles

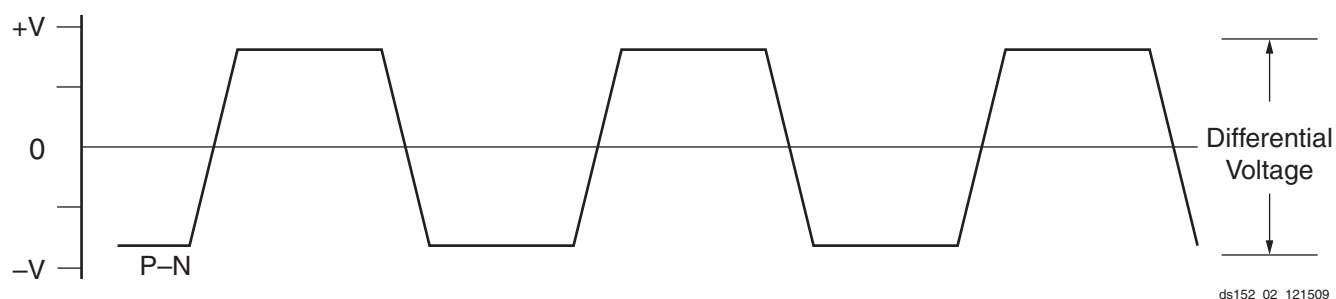


Figure 2: Differential Peak-to-Peak Voltage

Table 18 summarizes the DC specifications of the clock input of the GTX transceiver. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

Table 18: GTX Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	210	800	2000	mV
R_{IN}	Differential input resistance	90	100	130	Ω
C_{EXT}	Required external AC coupling capacitor	—	100	—	nF

GTX Transceiver Switching Characteristics

Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further information.

Table 19: GTX Transceiver Performance

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F_{GTXMAX}	Maximum GTX transceiver data rate	6.6	6.6	5.0	5.0	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	3.3 ⁽¹⁾	3.3 ⁽¹⁾	2.7	2.7	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	1.2	1.2	1.2	1.2	GHz

Notes:

- See Table 14 for MGTAVCC requirements when PLL frequency is greater than 2.7 GHz.

Table 20: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$F_{GTXDRPCLK}$	GTXDRPCLK maximum frequency	150	150	125	100	MHz

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 39: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{PIPECLK}	Pipe clock maximum frequency	250	250	250	250	MHz
F _{USERCLK}	User clock maximum frequency	500	500	250	250	MHz
F _{DRPCLK}	DRP clock maximum frequency	250	250	250	250	MHz

System Monitor Analog-to-Digital Converter Specification

Table 40: Analog-to-Digital Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
AV _{DD} = 2.5V ± 5%, V _{REFP} = 1.25V, V _{REFN} = 0V, ADCCLK = 5.2 MHz, T _j = -55°C to 125°C M-Grade, Typical values at T _j = +35°C						
DC Accuracy: All external input channels. Both unipolar and bipolar modes.						
Resolution			10	—	—	Bits
Integral Nonlinearity	INL		—	—	±1	LSBs
Differential Nonlinearity	DNL	No missing codes (T _{MIN} to T _{MAX}) Guaranteed Monotonic	—	—	±0.9	LSBs
Unipolar Offset Error ⁽¹⁾		Uncalibrated	—	±2	±30	LSBs
Bipolar Offset Error ⁽¹⁾		Uncalibrated measured in bipolar mode	—	±2	±30	LSBs
Gain Error		Uncalibrated - External Reference	—	±0.2	±2	%
		Uncalibrated - Internal Reference	—	±2	—	%
Bipolar Gain Error ⁽¹⁾		Uncalibrated - External Reference	—	±0.2	±2	%
		Uncalibrated - Internal Reference	—	±2	—	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	—	±10	—	LSBs
		Deviation from ideal transfer function. Internal reference	—	±20	—	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	—	±1	±2	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	—	±0.01	—	LSB/°C
DC Common-Mode Reject	CMRR _{DC}	V _N = V _{CM} = 0.5V ± 0.5V, V _P - V _N = 100mV	—	70	—	dB
Conversion Rate ⁽²⁾						
Conversion Time - Continuous	t _{CONV}	Number of CLK cycles	26	—	32	
Conversion Time - Event	t _{CONV}	Number of CLK cycles	—	—	21	
T/H Acquisition Time	t _{ACQ}	Number of CLK cycles	4	—	—	
DRP Clock Frequency	DCLK	DRP clock frequency	8	—	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	—	5.2	MHz
CLK Duty cycle			40	—	60	%

Table 40: Analog-to-Digital Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
Analog Inputs ⁽³⁾						
Dedicated Analog Inputs Input Voltage Range V _P - V _N		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	–0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	20	–	MHz
Auxiliary Analog Inputs Input Voltage Range V _{AUXP[0]} /V _{AUXN[0]} to V _{AUXP[15]} /V _{AUXN[15]} T _j = –55°C to 125°C		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	–0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	10	–	kHz
Input Leakage Current		A/D not converting, ADCCLK stopped	–	±1.0	–	µA
Input Capacitance			–	10	–	pF
On-chip Supply Monitor Error		V _{CCINT} and V _{CCAUX} with calibration enabled. External 1.25V reference T _j = –55°C to 125°C.	–	–	±1.0	% Reading
		V _{CCINT} and V _{CCAUX} with calibration enabled. Internal reference T _j = –40°C to 100°C. ⁽⁴⁾	–	±2	–	% Reading
On-chip Temperature Monitor Error		T _j = –55°C to +125°C with calibration enabled. External 1.25V reference.	–	–	±4	°C
		T _j = –40°C to +100°C with calibration enabled. Internal reference. ⁽⁴⁾	–	±5	–	°C
External Reference Inputs ⁽⁵⁾						
Positive Reference Input Voltage Range	V _{REFP}	Measured Relative to V _{REFN}	1.20	1.25	1.30	Volts
Negative Reference Input Voltage Range	V _{REFN}	Measured Relative to AGND	–50	0	100	mV
Input current	I _{REF}	ADCCLK = 5.2 MHz	–	–	100	µA
Power Requirements						
Analog Power Supply	AV _{DD}	Measured Relative to AV _{SS}	2.375	2.5	2.625	Volts
Analog Supply Current	AI _{DD}	ADCCLK = 5.2 MHz	–	–	12	mA

Notes:

- Offset errors are removed by enabling the System Monitor automatic gain calibration feature.
- See "System Monitor Timing" in [UG370: Virtex-6 FPGA System Monitor User Guide](#)
- See "Analog Inputs" in [UG370: Virtex-6 FPGA System Monitor User Guide](#) for a detailed description.
- These internal references are not specified over the junction temperature operating range for military (M) temperature devices.
- Any variation in the reference voltage from the nominal $V_{REFP} = 1.25\text{V}$ and $V_{REFN} = 0\text{V}$ will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by $\pm 4\%$ is permitted.

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVDCI_DV2_25	0.51	0.57	0.66	0.70	1.71	1.83	2.01	2.00	1.71	1.83	2.01	2.00	ns
LVDCI_DV2_18	0.55	0.61	0.71	0.73	1.69	1.81	2.00	1.98	1.69	1.81	2.00	1.98	ns
LVDCI_DV2_15	0.64	0.73	0.85	0.85	1.68	1.77	1.91	1.98	1.68	1.77	1.91	1.98	ns
LVPECL_25	0.85	0.94	1.09	1.08	1.38	1.49	1.65	1.64	1.38	1.49	1.65	1.64	ns
HSTL_I_12	0.81	0.91	1.06	1.06	1.48	1.60	1.78	1.74	1.48	1.60	1.78	1.74	ns
HSTL_I_DCI	0.81	0.91	1.06	1.06	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
HSTL_II_DCI	0.81	0.91	1.06	1.06	1.37	1.49	1.68	1.66	1.37	1.49	1.68	1.66	ns
HSTL_II_T_DCI	0.81	0.91	1.06	1.06	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
HSTL_III_DCI	0.81	0.91	1.06	1.06	1.34	1.45	1.62	1.61	1.34	1.45	1.62	1.61	ns
HSTL_I_DCI_18	0.81	0.91	1.06	1.06	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
HSTL_II_DCI_18	0.81	0.91	1.06	1.06	1.36	1.46	1.62	1.59	1.36	1.46	1.62	1.59	ns
HSTL_II_T_DCI_18	0.81	0.91	1.06	1.06	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
HSTL_III_DCI_18	0.81	0.91	1.06	1.06	1.43	1.54	1.69	1.67	1.43	1.54	1.69	1.67	ns
DIFF_HSTL_I_18	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.72	1.47	1.58	1.75	1.72	ns
DIFF_HSTL_I_DCI_18	0.85	0.94	1.09	1.08	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
DIFF_HSTL_I	0.85	0.94	1.09	1.08	1.45	1.56	1.73	1.71	1.45	1.56	1.73	1.71	ns
DIFF_HSTL_I_DCI	0.85	0.94	1.09	1.08	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
DIFF_HSTL_II_18	0.85	0.94	1.09	1.08	1.50	1.62	1.81	1.78	1.50	1.62	1.81	1.78	ns
DIFF_HSTL_II_DCI_18	0.85	0.94	1.09	1.08	1.36	1.46	1.62	1.59	1.36	1.46	1.62	1.59	ns
DIFF_HSTL_II_T_DCI_18	0.85	0.94	1.09	1.08	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
DIFF_HSTL_II	0.85	0.94	1.09	1.08	1.44	1.56	1.74	1.72	1.44	1.56	1.74	1.72	ns
DIFF_HSTL_II_DCI	0.85	0.94	1.09	1.08	1.37	1.49	1.68	1.66	1.37	1.49	1.68	1.66	ns
SSTL2_I_DCI	0.81	0.91	1.06	1.06	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
SSTL2_II_DCI	0.81	0.91	1.06	1.06	1.39	1.50	1.67	1.69	1.39	1.50	1.67	1.69	ns
SSTL2_II_T_DCI	0.81	0.91	1.06	1.06	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
SSTL18_I	0.81	0.91	1.06	1.06	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns
SSTL18_II	0.81	0.91	1.06	1.06	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns
SSTL18_I_DCI	0.81	0.91	1.06	1.06	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
SSTL18_II_DCI	0.81	0.91	1.06	1.06	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns
SSTL18_II_T_DCI	0.81	0.91	1.06	1.06	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
DIFF_SSTL2_I	0.85	0.94	1.09	1.08	1.49	1.60	1.77	1.74	1.49	1.60	1.77	1.74	ns
DIFF_SSTL2_I_DCI	0.85	0.94	1.09	1.08	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
DIFF_SSTL2_II	0.85	0.94	1.09	1.08	1.42	1.54	1.72	1.71	1.42	1.54	1.72	1.71	ns
DIFF_SSTL2_II_DCI	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.69	1.39	1.50	1.67	1.69	ns
DIFF_SSTL2_II_T_DCI	0.85	0.94	1.09	1.08	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns

Input Serializer/Deserializer Switching Characteristics

Table 51: ISERDES Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold for Control Lines							
T _{ISCKK_BITSIP} / T _{ISCKC_BITSIP}	BITSLIP pin Setup/Hold with respect to CLKDIV	0.07/ 0.15	0.08/ 0.16	0.09/ 0.17	0.09/ 0.17	0.14/ 0.17	ns
T _{ISCKK_CE} / T _{ISCKC_CE} ⁽²⁾	CE pin Setup/Hold with respect to CLK (for CE1)	0.20/ 0.03	0.25/ 0.04	0.27/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T _{ISCKK_CE2} / T _{ISCKC_CE2} ⁽²⁾	CE pin Setup/Hold with respect to CLKDIV (for CE2)	0.01/ 0.27	0.01 0.29	0.01/ 0.31	0.01/ 0.31	−0.05/ 0.35	ns
Setup/Hold for Data Lines							
T _{ISDCK_D} / T _{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.07/ 0.08	0.08/ 0.09	0.09/ 0.11	0.09/ 0.11	0.11/ 0.19	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin Setup/Hold with respect to CLK (using IODELAY) ⁽¹⁾	0.10/ 0.05	0.12/ 0.06	0.14/ 0.07	0.14/ 0.07	0.16/ 0.15	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin Setup/Hold with respect to CLK at DDR mode	0.07/ 0.08	0.08/ 0.09	0.09/ 0.11	0.09/ 0.11	0.11/ 0.19	ns
T _{ISDCK_DDLY_DDR} / T _{ISCKD_DDLY_DDR}	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY) ⁽¹⁾	0.10/ 0.05	0.12/ 0.06	0.14/ 0.07	0.14/ 0.07	0.16/ 0.15	ns
Sequential Delays							
T _{ISCKO_Q}	CLKDIV to out at Q pin	0.57	0.66	0.75	0.80	0.88	ns
Propagation Delays							
T _{ISDO_DO}	D input to DO output pin	0.19	0.22	0.25	0.25	0.28	ns

Notes:

- Recorded at 0 tap value.
- T_{ISCK_CE2} and T_{ISCK_CE2} are reported as $T_{ISCK_CE} / T_{ISCK_CE}$ in TRACE report.

Output Serializer/Deserializer Switching Characteristics

Table 52: OSERDES Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	0.23/ −0.10	0.28/ −0.10	0.31/ −0.10	0.35/ −0.10	0.36/ −0.15	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	0.44/ −0.10	0.51/ −0.09	0.56/ −0.08	0.60/ −0.08	0.68/ −0.15	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input Setup/Hold with respect to CLKDIV	0.25/ −0.10	0.27/ −0.09	0.31/ −0.08	0.31/ −0.08	0.47/ −0.15	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.17/ −0.03	0.20/ −0.03	0.22/ −0.03	0.27/ −0.03	0.27/ −0.04	ns
T _{OSCCK_S}	SR (Reset) input Setup with respect to CLKDIV	0.07	0.07	0.07	0.07	0.08	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.15/ −0.04	0.19/ −0.04	0.21/ −0.04	0.27/ −0.04	0.29/ −0.05	ns
Sequential Delays							
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.63	0.71	0.82	0.82	0.93	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.63	0.71	0.82	0.82	0.93	ns
Combinatorial							
T _{OSDO_TTQ}	T input to TQ Out	0.76	0.84	0.97	0.97	1.11	ns

Notes:

- T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 55: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.92	1.10	1.36	1.49	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	1.19	1.40	1.71	1.87	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS} /T _{DH}	A – D inputs to CLK	0.62/0.18	0.72/0.20	0.88/0.22	0.98/0.23	ns, Min
T _{AS} /T _{AH}	Address An inputs to clock	0.19/0.52	0.22/0.59	0.27/0.66	0.30/0.75	ns, Min
T _{WS} /T _{WH}	WE input to clock	0.27/0.00	0.32/0.00	0.40/0.00	0.47/–0.03	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK	0.28/–0.01	0.34/–0.01	0.41/–0.01	0.48/–0.05	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.70	0.82	1.00	1.04	ns, Min
T _{MCP}	Minimum clock period	1.40	1.64	2.00	2.08	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 56: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	1.11	1.30	1.58	1.74	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.37	1.60	1.93	2.12	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	1.08	1.27	1.55	1.74	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS} /T _{WH}	WE input	0.05/0.00	0.07/0.00	0.09/0.00	0.11/0.03	ns, Min
T _{CECK} /T _{CKCE}	CE input to CLK	0.06/–0.01	0.08/–0.01	0.10/–0.01	0.12/0.02	ns, Min
T _{DS} /T _{DH}	A – D inputs to CLK	0.64/0.18	0.76/0.21	0.94/0.24	1.07/0.23	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.60	0.70	0.85	0.89	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

Block RAM and FIFO Switching Characteristics

Table 57: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.60	1.79	2.08	2.36	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.60	0.66	0.75	0.83	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.62	2.89	3.30	3.73	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.71	0.77	0.86	0.94	ns, Max
T _{RCKO_CASC} and T _{RCKO_CASC_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.49	2.77	3.18	3.61	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	1.29	1.41	1.58	1.79	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.74	0.81	0.91	0.98	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.90	0.98	1.09	1.21	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (with output register)	0.62	0.68	0.76	0.82	ns, Max
	Clock CLK to BITERR (without output register)	2.21	2.46	2.84	3.23	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.86	0.94	1.06	1.18	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.73	0.79	0.90	1.00	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.76	0.82	0.92	1.02	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKC_ADDR} /T _{RCKC_ADDR}	ADDR inputs ⁽⁸⁾	0.47/ 0.27	0.53/ 0.29	0.62/ 0.32	0.66/ 0.34	ns, Min
T _{RDCK_DI} /T _{RCKD_DI}	DIN inputs ⁽⁹⁾	0.84/ 0.30	0.95/ 0.32	1.11/ 0.34	1.26/ 0.36	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.47/ 0.30	0.52/ 0.32	0.59/ 0.34	0.68/ 0.36	ns, Min
	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.68/ 0.30	0.75/ 0.32	0.85/ 0.34	0.97/ 0.36	ns, Min
	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.77/ 0.30	0.87/ 0.32	1.02/ 0.34	1.16/ 0.36	ns, Min
T _{RCKC_CLK} /T _{RCKC_CLK}	Inject single/double bit error in ECC mode	0.90/ 0.27	1.02/ 0.28	1.20/ 0.29	1.56/ 0.29	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	Block RAM Enable (EN) input	0.31/ 0.26	0.35/ 0.27	0.41/ 0.30	0.44/ 0.31	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.18/ 0.25	0.19/ 0.27	0.22/ 0.31	0.24/ 0.33	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/ 0.23	0.36/ 0.24	0.41/ 0.27	0.46/ 0.29	ns, Min

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
$T_{DSPDO_PCIN, CARRYCASCIN, MULTSIGNIN_PCOUT, CARRYCASCOUT, MULTSIGNOUT}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.28	1.46	1.72	1.72	2.06	ns
Clock to Outs from Output Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_PREG}$	CLK (PREG) to {P, CARRYOUT} output	0.38	0.43	0.50	0.50	0.57	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_PREG}$	CLK (PREG) to {CARRYCASCOUT, PCOUT, MULTSIGNOUT} output	0.50	0.56	0.66	0.66	0.76	ns
Clock to Outs from Pipeline Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_MREG}$	CLK (MREG) to {P, CARRYOUT} output	1.72	1.96	2.30	2.30	2.69	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_MREG}$	CLK (MREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.81	2.06	2.43	2.43	2.88	ns
$T_{DSPCKO_P, CARRYOUT_ADREG_MULT}$	CLK (ADREG) to {P, CARRYOUT} output	2.79	3.16	3.72	3.72	4.32	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_ADREG_MULT}$	CLK (ADREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	2.87	3.26	3.84	3.84	4.51	ns
Clock to Outs from Input Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_AREG, BREG_MULT}$	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	3.97	4.52	5.36	5.36	6.20	ns
$T_{DSPCKO_P, CARRYOUT_AREG, BREG}$	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	1.70	1.93	2.27	2.27	2.65	ns
$T_{DSPCKO_P, CARRYOUT_CREG}$	CLK (CREG) to {P, CARRYOUT} output	1.70	1.93	2.27	2.27	2.80	ns
$T_{DSPCKO_P, CARRYOUT_DREG_MULT}$	CLK (DREG) to {P, CARRYOUT} output	3.89	4.44	5.25	5.25	6.07	ns
Clock to Outs from Input Register Clock to Cascading Output Pins							
$T_{DSPCKO_ACOUT, BCOUT_AREG, BREG}$	CLK (AREG, BREG) to {P, CARRYOUT} output	0.66	0.76	0.89	0.89	1.01	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_AREG, BREG_MULT}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	4.05	4.63	5.49	5.49	6.39	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_AREG, BREG}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	1.79	2.03	2.40	2.40	2.84	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_DREG_MULT}$	CLK (DREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	3.98	4.54	5.38	5.38	6.26	ns
$T_{DSPCKO_PCOUT, CARRYCASCOUT, MULTSIGNOUT_CREG}$	CLK (CREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.78	2.03	2.40	2.40	2.99	ns

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{SMCKBY}	CCLK to BUSY out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	6	7	ns, Max
F _{SMCK}	Maximum Frequency with respect to nominal CCLK	100	100	100	70	MHz, Max
F _{RBCK}	Maximum Readback Frequency with respect to nominal CCLK	100	100	100	60	MHz, Max
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK	55	55	55	60	%
Boundary-Scan Port Timing Specifications						
T _{TAPTCK} /T _{TCKTAP}	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	3.0/2.0	4.0/2.0	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output valid at 2.5V	6	6	6	7	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	6	7	ns, Max
F _{TCK}	Maximum configuration TCK clock frequency	66	66	66	33	MHz, Max
F _{TCKB_MIN}	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	15	15	MHz, Min
F _{TCKB}	Maximum boundary-scan TCK clock frequency	66	66	66	33	MHz, Max
BPI Master Flash Mode Programming Switching						
T _{BPICCO} ⁽²⁾	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	6	7	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	6	7	ns
T _{BPIDCC} /T _{BPICCD}	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns
T _{INITADDR}	Minimum period of initial ADDR[25:0] address cycles	3	3	3	3	CCLK cycles
SPI Master Flash Mode Programming Switching						
T _{SPIDCC} /T _{SPIDCCD}	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	3.0/0.0	3.5/0.0	ns
T _{SPICCM}	MOSI clock to out at 2.5V	6	6	6	7	ns
	MOSI clock to out at 1.8V	6	6	6	7	ns
T _{SPICFC}	FCS_B clock to out at 2.5V	6	6	6	7	ns
	FCS_B clock to out at 1.8V	6	6	6	7	ns
T _{FSINIT} /T _{FSINITH}	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	2	2	µs
CCLK Output (Master Modes)						
T _{MCCKL}	Master CCLK clock Low time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	2.5	2.5	2.5	2.5	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	2.5	2.5	2.5	2.5	ns, Min
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
F _{DCK}	Maximum frequency for DCLK	200	200	200	200	MHz
T _{MMCMCKD_DADDR} / T _{MMCMCKD_DADDR}	DADDR Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns

Table 64: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
RST _{MINPULSE}	Minimum Reset Pulse Width	1.5	1.5	1.5	1.5	ns
F _{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized ⁽⁹⁾	550	500	450	450	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300	300	300	300	MHz
F _{PFDMIN}	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	135	135	135	135	MHz
	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	10	10	10	10	MHz
T _{FBDELAY}	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
T _{MMCMCK_PSEN} / T _{MMCMCKD_PSEN}	Setup and Hold of Phase Shift Enable	1.04 0.00	1.04 0.00	1.04 0.00	1.04 0.00	ns
T _{MMCMCK_PINCDEC} / T _{MMCMCKD_PINCDEC}	Setup and Hold of Phase Shift Increment/Decrement	1.04 0.00	1.04 0.00	1.04 0.00	1.04 0.00	ns
T _{MMCMCKO_PSDONE}	Phase Shift Clock-to-Out of PSDONE	0.32	0.34	0.38	0.38	ns

Notes:

1. When DIVCLK_DIVIDE = 3 or 4, F_{INMAX} is 315 MHz.
2. This duty cycle specification does not apply to the GTH_QUAD (GTH) to MMCM connection. The GTH transceivers drive the MMCMs at the following maximum frequencies: 323 MHz for -1 speed grade devices, 350 MHz for -2 speed grade devices, or 350 MHz for -3 speed grade devices.
3. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
4. The static offset is measured between any MMCM outputs with identical phase.
5. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
6. Includes global clock buffer.
7. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.
8. When CASCADE4_OUT = TRUE, F_{OUTMIN} is 0.036 MHz.
9. In ISE software 12.3 (or earlier versions supporting the Virtex-6 family), the phase frequency detector Optimized bandwidth setting is equivalent to the High bandwidth setting. Starting with ISE software 12.4, the Optimized bandwidth setting is automatically adjusted to Low when the software can determine that the phase frequency detector input is less than 135 MHz.

Table 66: Global Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> MMCM.							
T _{ICKOFFMMCMGC}	Global Clock Input and OUTFF <i>with</i> MMCM	XC6VLX75T	2.34	2.50	2.77	2.85	ns
		XC6VLX130T	2.35	2.51	2.78	2.87	ns
		XC6VLX195T	2.36	2.52	2.79	2.88	ns
		XC6VLX240T	2.36	2.52	2.79	2.88	ns
		XC6VLX365T	2.37	2.53	2.79	2.89	ns
		XC6VLX550T	N/A	2.55	2.82	2.93	ns
		XC6VLX760	N/A	2.54	2.82	2.92	ns
		XC6VSX315T	2.35	2.51	2.79	2.87	ns
		XC6VSX475T	N/A	2.43	2.70	2.79	ns
		XC6VHX250T	2.36	2.53	2.80	N/A	ns
		XC6VHX255T	2.46	2.63	2.91	N/A	ns
		XC6VHX380T	2.39	2.59	2.83	N/A	ns
		XC6VHX565T	N/A	2.54	2.81	N/A	ns
		XQ6VLX130T	N/A	2.51	2.78	2.87	ns
		XQ6VLX240T	N/A	2.52	2.79	2.88	ns
		XQ6VLX550T	N/A	N/A	2.82	2.93	ns
		XQ6VSX315T	N/A	2.51	2.79	2.87	ns
		XQ6VSX475T	N/A	N/A	2.70	2.79	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 70: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Clock-capable Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSMMCMCC} / T _{PHMMCMCC}	No Delay Clock-capable Clock Input and IFF ⁽²⁾ with MMCM	XC6VLX75T	1.56/ −0.25	1.69/ −0.25	1.86/ −0.25	1.91/ −0.15	ns
		XC6VLX130T	1.64/ −0.25	1.78/ −0.25	1.95/ −0.25	2.00/ −0.14	ns
		XC6VLX195T	1.65/ −0.24	1.79/ −0.24	1.96/ −0.24	2.01/ −0.15	ns
		XC6VLX240T	1.65/ −0.24	1.79/ −0.24	1.96/ −0.24	2.01/ −0.15	ns
		XC6VLX365T	1.66/ −0.25	1.79/ −0.25	1.97/ −0.25	2.02/ −0.15	ns
		XC6VLX550T	N/A	1.97/ −0.24	2.16/ −0.24	2.19/ −0.14	ns
		XC6VLX760	N/A	2.39/ −0.20	2.63/ −0.20	2.21/ −0.10	ns
		XC6VSX315T	1.67/ −0.25	1.80/ −0.25	1.98/ −0.25	2.03/ −0.16	ns
		XC6VSX475T	N/A	1.98/ −0.29	2.17/ −0.29	2.21/ −0.20	ns
		XC6VHX250T	1.63/ −0.24	1.76/ −0.24	1.94/ −0.24	N/A	ns
		XC6VHX255T	1.63/ −0.19	1.76/ −0.19	1.99/ −0.19	N/A	ns
		XC6VHX380T	1.80/ −0.23	1.94/ −0.23	2.13/ −0.23	N/A	ns
		XC6VHX565T	N/A	1.94/ −0.08	2.13/ −0.08	N/A	ns
		XQ6VLX130T	N/A	1.78/ −0.25	1.95/ −0.25	2.00/ −0.14	ns
		XQ6VLX240T	N/A	1.79/ −0.24	1.96/ −0.24	2.01/ −0.15	ns
		XQ6VLX550T	N/A	N/A	2.16/ −0.24	2.19/ −0.14	ns
		XQ6VSX315T	N/A	1.80/ −0.25	1.98/ −0.25	2.03/ −0.16	ns
		XQ6VSX475T	N/A	N/A	2.17/ −0.29	2.21/ −0.20	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch
- Use IBIS to determine any duty-cycle distortion incurred using various standards.

Clock Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Virtex-6 FPGA clock transmitter and receiver data-valid windows.

Table 71: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{DCD_CLK}	Global Clock Tree Duty Cycle Distortion ⁽¹⁾	All	0.12	0.12	0.12	0.12	ns
T_{CKSKEW}	Global Clock Tree Skew ⁽²⁾	XC6VLX75T	0.15	0.16	0.18	0.17	ns
		XC6VLX130T	0.25	0.26	0.29	0.28	ns
		XC6VLX195T	0.26	0.27	0.31	0.30	ns
		XC6VLX240T	0.26	0.27	0.31	0.30	ns
		XC6VLX365T	0.28	0.29	0.31	0.31	ns
		XC6VLX550T	N/A	0.50	0.54	0.54	ns
		XC6VLX760	N/A	0.51	0.56	0.56	ns
		XC6VSX315T	0.27	0.28	0.32	0.30	ns
		XC6VSX475T	N/A	0.39	0.44	0.42	ns
		XC6VHX250T	0.25	0.26	0.29	N/A	ns
		XC6VHX255T	0.35	0.37	0.41	N/A	ns
		XC6VHX380T	0.45	0.47	0.52	N/A	ns
		XC6VHX565T	N/A	0.46	0.51	N/A	ns
		XQ6VLX130T	N/A	0.26	0.29	0.28	ns
		XQ6VLX240T	N/A	0.27	0.31	0.30	ns
		XQ6VLX550T	N/A	N/A	0.54	0.54	ns
		XQ6VSX315T	N/A	0.28	0.32	0.30	ns
		XQ6VSX475T	N/A	N/A	0.44	0.42	ns
T_{DCD_BUFIO}	I/O clock tree duty cycle distortion	All	0.08	0.08	0.08	0.08	ns
T_{BUFIO_SKEW}	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.02	ns
T_{BUFIO_SKEW2}	I/O clock tree skew across three clock regions	All	0.10	0.12	0.23	0.12	ns
T_{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	0.15	ns

Notes:

1. These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
2. The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

Table 73: Sample Window

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	All	510	560	610	670	ps
T_{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO ⁽²⁾	All	300	350	400	440	ps

Notes:

1. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
 These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IODELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 74: Pin-to-Pin Setup/Hold and Clock-to-Out

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO						
T _{PSCS} /T _{PHCS}	Setup/Hold of I/O clock	−0.28/1.09	−0.28/1.16	−0.28/1.33	−0.18/1.79	ns
Pin-to-Pin Clock-to-Out Using BUFIO						
T _{ICKOFCs}	Clock-to-Out of I/O clock	4.22	4.59	5.22	5.63	ns

Revision History

The following table shows the revision history for this document:

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
07/16/09	1.1	Revised the maximum V_{CCAUX} and V_{IN} numbers in Table 2, page 2 . Removed empty column from Table 3, page 3 . Revised specifications on Table 20, page 13 . Updated Table 38, page 22 and added notes 1 and 2. Revised T_{DLYCCO_RDY} , $T_{IDELAYCTRL_RPW}$, and $T_{IDELAYPAT_JIT}$ in Table 53, page 41 . Updated Table 58, page 46 to more closely match the DSP48E1 speed specifications. Updated T_{TAPTCK}/T_{TCKTAP} in Table 59, page 49 . Updated XC6VLX130T parameters in Table 68 through Table 70, page 59 .
08/19/09	1.2	Added values for -1L voltages and speed grade in all pertinent tables. Added V_{FS} and notes to Table 1 and Table 2 . Removed DV_{PPIN} from the example in Figure 2 . Added networking applications to Table 41, page 25 . Changed and added to the block RAM F_{MAX} section in Table 57, page 44 including removing Note 12. Changed F_{PFDMAX} values and corrected units for $T_{STATPHAOFFSET}$ and $T_{OUTDUTY}$ in Table 64, page 52 . Updated Table 71, page 60 .
09/16/09	2.0	Added Virtex-6 HXT devices to entire document including GTH Transceiver Specifications . Updated speed specifications as described in Switching Characteristics , includes changes in Table 51 , Table 57 , Table 58 , and Table 66 through Table 70 . Comprehensive changes to Table 14 , Table 15 , and Table 16 . Added conditions to DV_{PPOUT} and revised description of T_{OSKEW} in Table 17 . Removed V_{ISE} specification and note from Table 18 . Added note 3 to Table 23 . Updated note 3 in Table 24 . Updated LVCMOS25 delays in Table 44 . Updated specification for T_{IOTPHZ} in Table 46 . Removed $T_{BUFHSKEW}$ from Table 71, page 60 and added values for $T_{BUFIOSKEW}$. Added values in Table 74 .